Notice of References Cited	Application/Control No. 10/596,849	Applicant(s)/Patent Under Reexamination OISHI, KEIICHIRO		
Notice of References offed	Examiner	Art Unit	Page 1 of 1	
	Sikyin Ip	1793		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,110,132	08-1978	Parikh et al.	148/434
*	В	US-4,826,736	05-1989	Nakamura et al.	428/613
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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